



COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(on)}	I _D T _A = 25°C
Q1	30V	60mΩ @ V _{GS} = 10V	3.4A
QT	30 V	100mΩ @ $V_{GS} = 4.5V$	2.7A
02	201/	95m Ω @ V _{GS} = -10V	-2.8A
Q2	-30V	140mΩ @ V _{GS} = -4.5V	-2.3A

Description and Applications

This new generation MOSFET has been designed to minimize the onstate resistance ($R_{DS(on)}$) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

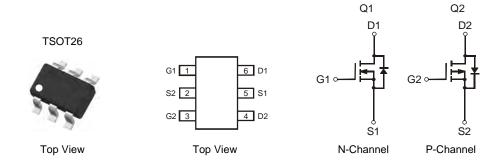
- Backlighting
- DC-DC Converters
- Power management functions

Features and Benefits

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Totally Lead-Free Finish; RoHS compliant (Note 1)
- Halogen and Antimony Free. "Green" Device (Note 2)
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

- Case: TSOT26
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See Diagram
- Terminals: Finish Matte Tin annealed over Copper leadframe.
 Solderable per MIL-STD-202, Method 208
- Weight: 0.013 grams (approximate)



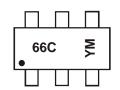
Ordering Information (Note 3)

-			
	Part Number	Case	Packaging
	DMG6602SVT-7	TSOT26	3000 / Tape & Reel

Notes:

- 1. EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. All applicable RoHS exemptions applied.
- 2. Halogen and Antimony free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 3. For packaging details, go to our website at http://www.diodes.com.

Marking Information



66C = Product Type Marking Code YM = Date Code Marking Y = Year (ex: X = 2010) M = Month (ex: 9 = September)

Date Code Key

Year	2010		2011	2012		2013	2014		2015	2016		2017
Code	X		Υ	Z		Α	В		С	D		E
Month	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	0	N	D



Maximum Ratings − Q1 @TA = 25°C unless otherwise specified

Characteristi	Symbol	Value	Unit		
Drain-Source Voltage			V _{DSS}	30	V
Gate-Source Voltage	V _{GSS}	±20	V		
Continuous Drain Current (Note 5) V _{GS} = 10V	Steady State	T _A = 25°C T _A = 70°C	I _D	3.4 2.7	А
Continuous Drain Current (Note 5) V _{GS} = 4.5V	I _D	2.7 2.2	А		
Maximum Continuous Body Diode Forward Current (Is	1.5	Α		
Pulsed Drain Current (Note 5)			I _{DM}	25	A

Maximum Ratings - Q2 @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Unit		
Drain-Source Voltage	Drain-Source Voltage				
Gate-Source Voltage	V _{GSS}	±20	V		
Continuous Drain Current (Note 5) V _{GS} = -10V	Steady State	T _A = 25°C T _A = 70°C	I _D	-2.8 -2.4	А
Continuous Drain Current (Note 5) V _{GS} = -4.5V	I _D	-2.3 -2.1	А		
Maximum Continuous Body Diode Forward Current (Is	-1.5	А		
Pulsed Drain Current (Note 5)	I _D	-20	Α		

Thermal Characteristics

Characteristic	Symbol	Value	Units		
Total Power Dissipation (Note 4)	T _A = 25°C	Б	0.84	W	
Total Power Dissipation (Note 4)	T _A = 70°C	P _D	0.52		
Thermal Resistance, Junction to Ambient (Note 4)	Steady state	В	155	°C/W	
Thermal Resistance, Junction to Ambient (Note 4)	t<10s	$R_{ hetaJA}$	109		
Total Power Dissipation (Note 5)	$T_A = 25^{\circ}C$	PD	1.27	W	
Total Fower Dissipation (Note 3)	$T_A = 70^{\circ}C$	FD	0.8	VV	
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	В	102		
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{\theta JA}$	71	°C/W	
Thermal Resistance, Junction to Case (Note 5)		$R_{ heta JC}$	34		
Operating and Storage Temperature Range		$T_{J_1}T_{STG}$	-55 to +150	ů	

4. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout. 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

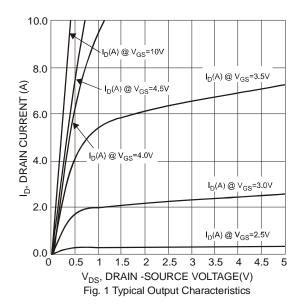


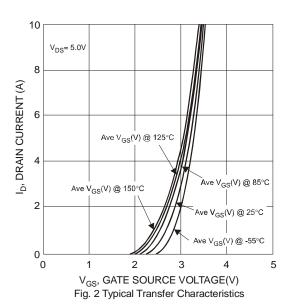
Electrical Characteristics - Q1 NMOS@ TA = 25°C unless otherwise stated

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)		-	ā.		a.	
Drain-Source Breakdown Voltage	BV _{DSS}	30	-	-	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	-	-	1.0	μΑ	$V_{DS} = 24V$, $V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	-	-	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 6)						
Gate Threshold Voltage	V _{GS(th)}	1.0	-	2.3	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	R _{DS (ON)}	-	38 55	60 100	mΩ	$V_{GS} = 10V, I_D = 3.1A$
Forward Transfer Admittance	Y _{fs}	-	4	-	S	$V_{GS} = 4.5V, I_D = 2A$ $V_{DS} = 5V, I_D = 3.1A$
Diode Forward Voltage	V _{SD}	-	0.8	1	V	$V_{GS} = 0V, I_{S} = 1A$
DYNAMIC CHARACTERISTICS (Note 7)	•		,		•	
Input Capacitance	C _{iss}	-	290	400		V _{DS} = 15V, V _{GS} = 0V, f = 1.2MHz
Output Capacitance	Coss	-	40	80	pF	
Reverse Transfer Capacitance	C _{rss}	-	40	80		
Gate Resistance	Rg	-	1.4	-	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (V _{GS} = 4.5V)	Qg	-	4	6		$V_{DS} = 15V$, $V_{GS} = 4.5V$, $I_{D} = 3.1A$
Total Gate Charge (V _{GS} = 10V)	Qg	-	9	13		
Gate-Source Charge	Qgs	-	1.2	-	nC	$V_{DS} = 15V, V_{GS} = 10V, I_{D} = 3A$
Gate-Drain Charge	Q_{gd}	-	1.5	-		
Turn-On Delay Time	t _{D(on)}	-	3	-		
Turn-On Rise Time	t _r	-	5	-		$V_{GS} = 10V, V_{DS} = 15V,$
Turn-Off Delay Time	t _{D(off)}	-	13	-	ns	$R_G = 3\Omega$, $R_L = 4.7\Omega$
Turn-Off Fall Time	t _f	-	3	-		

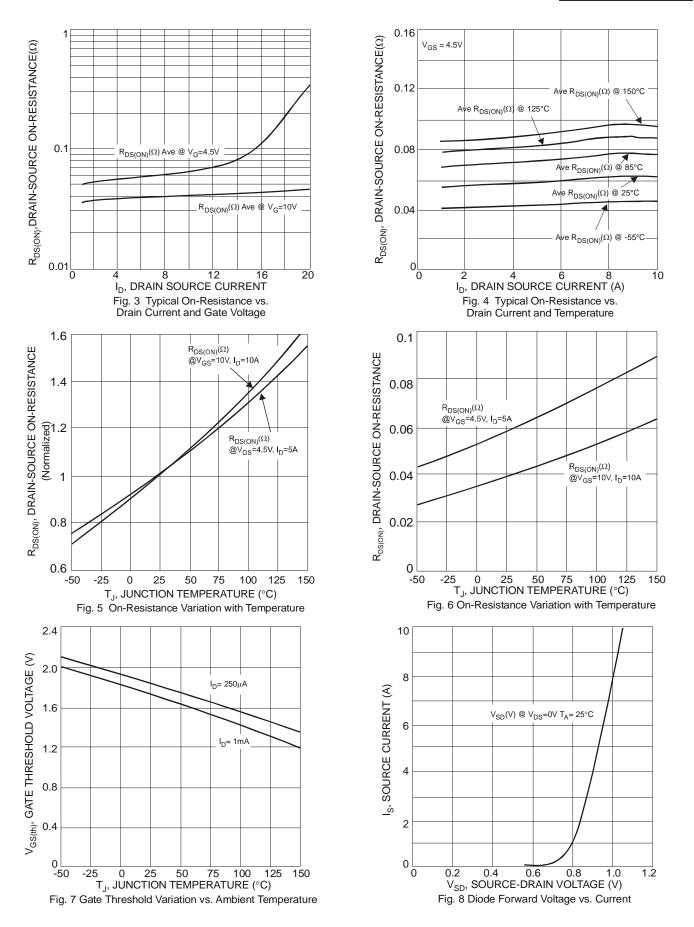
Notes:

- 6. Short duration pulse test used to minimize self-heating effect. 7. Guaranteed by design. Not subject to product testing.

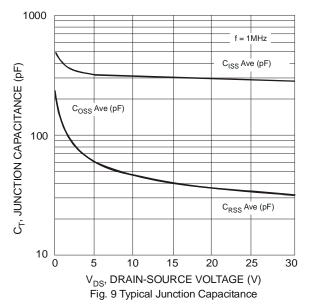


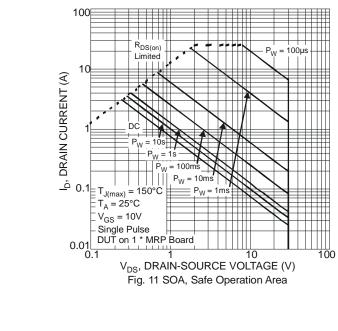


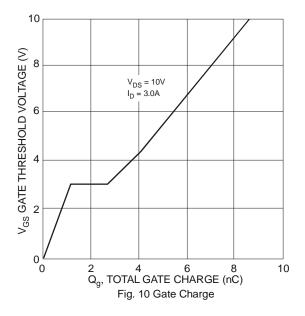












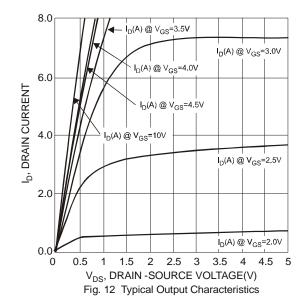


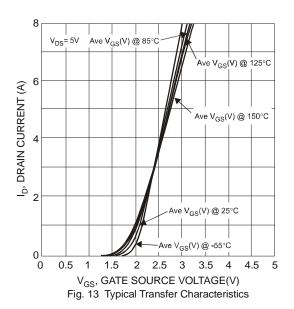
Electrical Characteristics – Q2 PMOS@ TA = 25°C unless otherwise stated

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)				-		
Drain-Source Breakdown Voltage	BV _{DSS}	-30	-	-	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	-	-	-1.0	μΑ	$V_{DS} = -24V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	-	-	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 6)						
Gate Threshold Voltage	$V_{GS(th)}$	-1.0	-	-2.3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
Static Drain-Source On-Resistance			73	95	mΩ	$V_{GS} = -10V, I_D = -2.7A$
Static Drain-Source On-Resistance	R _{DS} (ON)	-	99	140	11152	$V_{GS} = -4.5V, I_D = -2A$
Forward Transfer Admittance	Y _{fs}	-	6	-	S	$V_{DS} = -5V, I_{D} = -2.7A$
Diode Forward Voltage	V _{SD}	-	-0.8	-1.0	V	$V_{GS} = 0V, I_{S} = -1A$
DYNAMIC CHARACTERISTICS (Note 7)						
Input Capacitance	C _{iss}	-	350	420		$V_{DS} = -15V, V_{GS} = 0V,$ f = 1.2MHz
Output Capacitance	Coss	-	50	100	pF	
Reverse Transfer Capacitance	C _{rss}	-	45	80		
Gate Resistance	R_g	-	17.1	-	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (V _{GS} = -4.5V)	Qg	-	4	6		$V_{DS} = -15V$, $V_{GS} = -4.5V$, $I_{D} = -3A$
Total Gate Charge (V _{GS} = -10V)	Qq	-	7	9		
Gate-Source Charge	Q _{gs}	-	0.9	-	nC	$V_{DS} = -15V, V_{GS} = -10V, I_{D} = -3A$
Gate-Drain Charge	Q _{gd}	-	1.2	-		
Turn-On Delay Time	t _{D(on)}	-	4.8	-		
Turn-On Rise Time	t _r	-	7.3	-		$V_{GS} = -10V, V_{DS} = -15V,$
Turn-Off Delay Time	t _{D(off)}	-	20	-	ns	$R_G = 6\Omega$, $R_L = 15\Omega$
Turn-Off Fall Time	t _f	-	13	-		

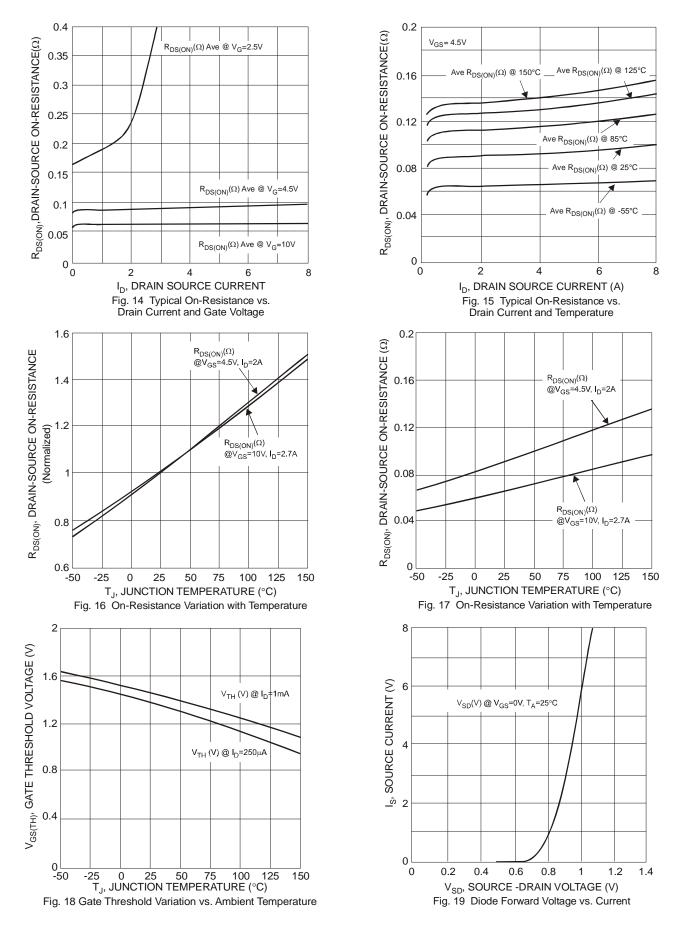
Notes:

- 6. Short duration pulse test used to minimize self-heating effect. 7. Guaranteed by design. Not subject to production testing.

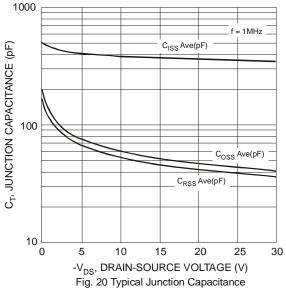


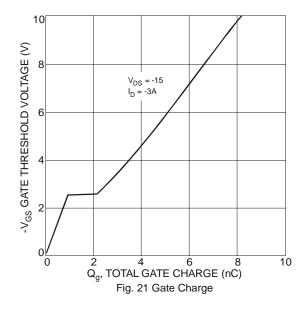


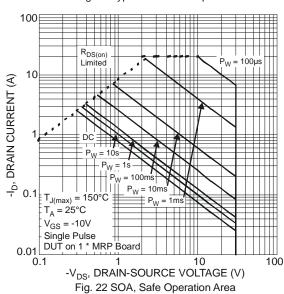


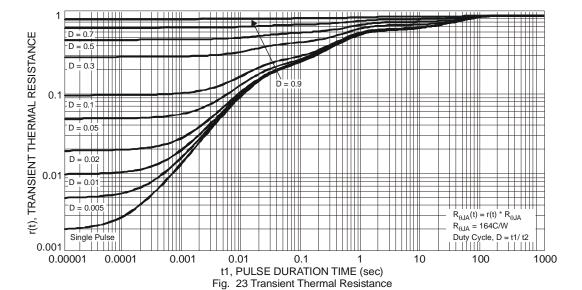






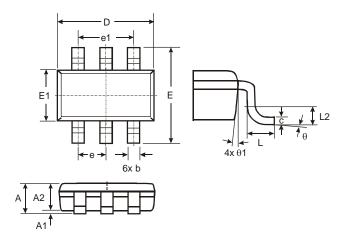






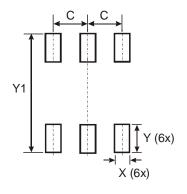


Package Outline Dimensions



	TSOT26							
Dim	Min	Max	Тур					
Α	-	1.00	_					
A 1	0.01	0.10	_					
A2	0.84	0.90	_					
D	-	_	2.90					
Е	_	_	2.80					
E1	E1 –		1.60					
b	b 0.30		_					
C	c 0.12		_					
е	-	_	0.95					
e1	-	_	1.90					
L	0.30	0.50						
L2	-	_	0.25					
θ	0°	8°	4°					
θ1	4°	12°	_					
All D	imensi	ons in	mm					

Suggested Pad Layout



Dimensions	Value (in mm)
С	0.950
Х	0.700
Υ	1.000
Y1	3.199



IMPORTANT NOTICE

DIODES INCORPORATED MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARDS TO THIS DOCUMENT, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION).

Diodes Incorporated and its subsidiaries reserve the right to make modifications, enhancements, improvements, corrections or other changes without further notice to this document and any product described herein. Diodes Incorporated does not assume any liability arising out of the application or use of this document or any product described herein; neither does Diodes Incorporated convey any license under its patent or trademark rights, nor the rights of others. Any Customer or user of this document or products described herein in such applications shall assume all risks of such use and will agree to hold Diodes Incorporated and all the companies whose products are represented on Diodes Incorporated website, harmless against all damages.

Diodes Incorporated does not warrant or accept any liability whatsoever in respect of any products purchased through unauthorized sales channel. Should Customers purchase or use Diodes Incorporated products for any unintended or unauthorized application, Customers shall indemnify and hold Diodes Incorporated and its representatives harmless against all claims, damages, expenses, and attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized application.

Products described herein may be covered by one or more United States, international or foreign patents pending. Product names and markings noted herein may also be covered by one or more United States, international or foreign trademarks.

LIFE SUPPORT

Diodes Incorporated products are specifically not authorized for use as critical components in life support devices or systems without the express written approval of the Chief Executive Officer of Diodes Incorporated. As used herein:

- A. Life support devices or systems are devices or systems which:
 - 1. are intended to implant into the body, or
 - 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
- B. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or to affect its safety or effectiveness.

Customers represent that they have all necessary expertise in the safety and regulatory ramifications of their life support devices or systems, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of Diodes Incorporated products in such safety-critical, life support devices or systems, notwithstanding any devices- or systems-related information or support that may be provided by Diodes Incorporated. Further, Customers must fully indemnify Diodes Incorporated and its representatives against any damages arising out of the use of Diodes Incorporated products in such safety-critical, life support devices or systems.

Copyright © 2012, Diodes Incorporated

www.diodes.com

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for diodes incorporated manufacturer:

Other Similar products are found below:

1.5KE62A-T MMSZ5232BQ-13-F DMN2065UW-7 AH3782-SA-7 AP7365-39WG-7 6A10-T MBRB10100CT AZ1117EH-5.0TRG1
AZV3002S-13 PAM2863EV1 SBRT25U60SLP-13 LM2904AQM8-13 GBPC1506 GBU804 GBU808 BCR401UW6-7 DMP4013LFG-7
DMTH6009LK3Q-13 SB560-T AP3125AKTR-G1 FMMT491ATA AZV832MMTR-G1 6A6-T BZX84C5V1TS-7-F DMP6180SK3-13
BZT52C15LP-7 74LVC1G58W6-7 DDTC114ELP-7 BAS40 1N5402-T ZMR330FTA ZVN4525E6TA SBR40100CT FZT605TA
BZT52C2V4Q-7-F BZX84C15-13-F BZX84C3V9Q-7-F BZX84C4V7-13-F BZX84C5V1-13-F BZX84C3V9 ZXLD1370/1EV4
AP64501SP-EVM AP63203WU-EVM AP63200WU-EVM AP63201WU-EVM AP63356DV-EVM DMN30H4D0L-7 DFLT48A-7
ZVNL110A ZXSC100N8TA